

Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/662,554	PHAM, HIEP THE
	Examiner Hai L. Nguyen	Art Unit 2816

ISSUE CLASSIFICATION			
ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
327	156	327	162 148
INTERNATIONAL CLASSIFICATION			
H	0	3	L 7/06
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Hai L. Nguyen (Assistant Examiner)		4/29/2005 (Date)	TIMOTHY P. CALLAHAN SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 <i>[Signature]</i> (Primary Examiner)
April Smith 5/4/05 (Legal Instruments Examiner)		(Date)	Total Claims Allowed: 34 O.G. Print Claim(s) 1
			O.G. Print Fig. 3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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